Hua Zhou, Ph.D.

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Professional Experience

- 01/2010-Present Argonne National Laboratory
 Postdoctoral Research Fellow, Chemical Science and Engineering Division
- 10/2007-12/2009 Brookhaven National Laboratory
 Postdoctoral Research Associate, National Synchrotron Light Source
- 09/2002 10/2007 University of Vermont
 - 06/2003-10/2007 Research Assistant, Physics Department and Materials Science Program
 - 09/2002-05/2003 Teaching Assistant, Physics Department
- 03/2001-06/2002 Beijing University of Technology, China

Research Assistant, School of Materials Science and Engineering

Education

University of Vermont, Burlington, VT 09/2002 – 10/2007 Ph.D. in Materials Science, 10/2007 Beijing University of Technology, Beijing, China 09/1997 – 06/2002 B.S. in Materials Science & Engineering, 06/2002

Research Highlights

- Probing carbon electrode fluid electrolytes interfacial processes underlying electrochemical energy storage systems by synchrotron x-ray interfacial scattering
- Atomic structure imaging of complex oxide oxide interface systems by synchrotron x-ray surface diffraction and phase retrieval methods
- Investigated energetic thin film growth and surface processes *in-situ* and in real-time by synchrotron x-ray scattering
- Prepared boron nitride thin films and investigated field emission properties

Recognition and Honors

NSLS/CFN Poster Session Award Winner	2009
Vermont EPSCoR Graduate Research Fellowship	2003
Summa Cum Laude (BUT)	2002
SONY Award for Merits	2000

Publications

- H. Zhou and Y. Yacoby and R. Pindak and V. Butko and G. Logvenov and I. Bozovic, "Anomalous expansion of the copper apical oxygen distance in superconducting cuprate bilayers", Proceedings of the National Academy of Sciences of the United States of America, in press (2010).
- R. L. Headrick and H. Zhou, "Ripple formation and smoothening on insulating surfaces", Journal of Physics: Condense Matter 21, 224005 (2009).
- H. Zhou and L. Zhou and R. L. Headrick and G. Özaydin and K. F. Ludwig Jr., "Mechanisms of ultra-smoothing of oxide surfaces induced by ion-beam erosion", Physical Review B 78, 165404 (2008).
- H. Zhou and Y. P. Wang and L. Zhou and R. L. Headrick and A. S. Özcan and Y. Y. Wang and G. Özaydin and K. F. Ludwig Jr, "Wavelength tunability of ion-bombardment-induced ripples on sapphire investigated with small-angle x-ray scattering and atomic force microscopy", Physical Review B 75, 155416 (2007).
- Y. P. Wang and H. Zhou and L. Zhou and R. L. Headrick and A. Macrander and A. S. Özcan and K. F. Ludwig Jr., "Interface roughness evolution in sputtered WSi₂/Si multilayers", Journal of Applied Physics 101, 023503 (2007).
- R. Z. Wang and H. Zhou and X. M. Song and B. Wang and H. Wang and H. Yan, "Effects of phase formation on electron field emission from BN films", Journal of Crystal Growth 291, 18 (2006).
- A. C. Mayer and R. Ruiz and H. Zhou and R. L. Headrick and A. Kazimirov and G. G. Malliaras, "Growth dynamics of pentacene thin films: Real-time synchrotron x-ray scattering study", Physical Review B 73, 205307 (2006).
- H. Zhou and R. L. Headrick and B. R. Wang and Y. P. Wang and G. P. Carpenter and A. C. Mayer and M. Lloyd and G. Malliaras and A. Kazimirov and J. E. Anthony, "Growth of macroscopic-area single crystal polyacene thin films on arbitrary substrates", unpublished (2005).
- H. Zhou and R. Z. Wang and A. P. Wang and M. Wang and H. Wang and B. Wang and H. Yan, "Dependence of oriented BN films on Si(100) substrate temperature", Journal of Crystal Growth 241, 261 (2002).
- H. Zhou and X. H. Li and A. P. Huang and B. Wang and H. Yan, "Effects of substrate surface electric field on growth of cubic boron nitride films", Rare Metal Materials and Engineering 30, 643 Suppl. S (2001).